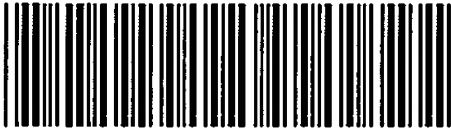


Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination	
	09/893,897	TOYAMA ET AL.	
	Examiner	Art Unit	
	Phu K. Nguyen	2673	

SEARCHED			
Class	Subclass	Date	Examiner
345	419	7/10/2005	PN
	422	7/10/2005	PN
	426	7/10/2005	PN
	600	7/10/2005	PN
707	526	7/10/2005	PN
358	357	7/10/2005	PN
382	303	7/10/2005	PN

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
WEST search SEE ATTACHED	7/10/2005	PN
Nonpatent (IEEE, ACM) search SEE ATTACHED	7/10/2005	PN
Inventor Name search SEE ATTACHED	7/10/2005	PN